

Erratum

Bond strength of a self-adhesive resinous cement to root dentin irradiated with 980-nm diode laser.

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Due to a mistake by the authors, incorrect figures 2, 3 and 4 were published. The correct figures and legends are shown below.

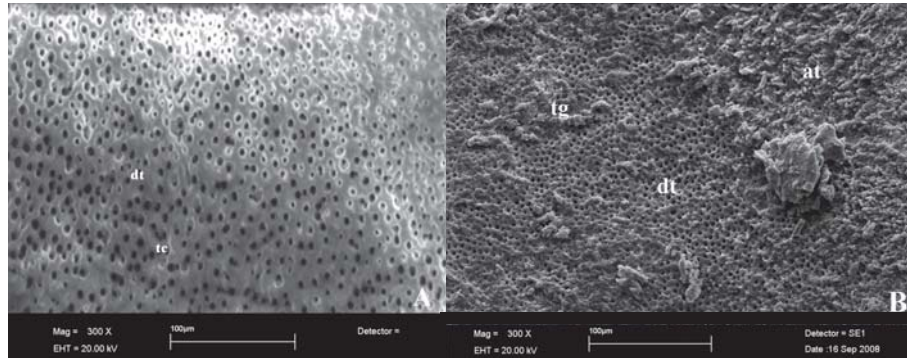


Figure 2. (A) Micrograph showing sample of CP/LI group. Exposure of dentinal tubules (dt) and topographic changes (tc) in substrate after diode LI. (B) Sample of RX/LI group. Exposure of dentinal tubules after LI (dt), adhesive tags (at) and topographic changes in substrate (tg).

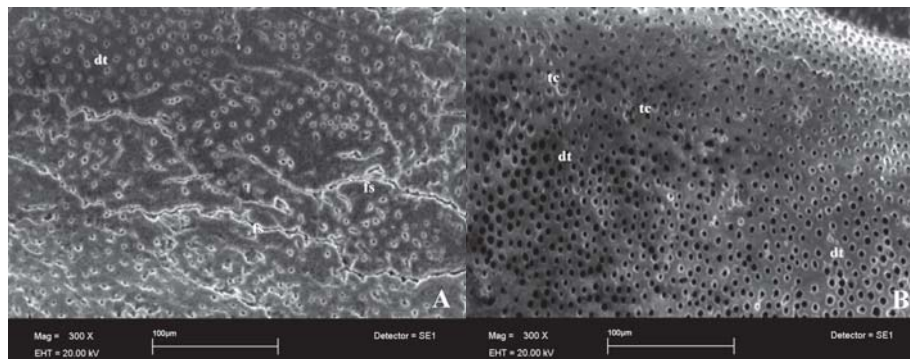


Figure 3. (A) Micrograph showing sample of RX/LI group. Topographic changes in substrate (fissures - fs) after diode LI. Absence of smear layer on the root dentin of RX/LI group and exposure of dentinal tubules (dt). (B) Sample of CP/LI group. Exposure of dentinal tubules (dt) and topographic changes in substrate (tg).

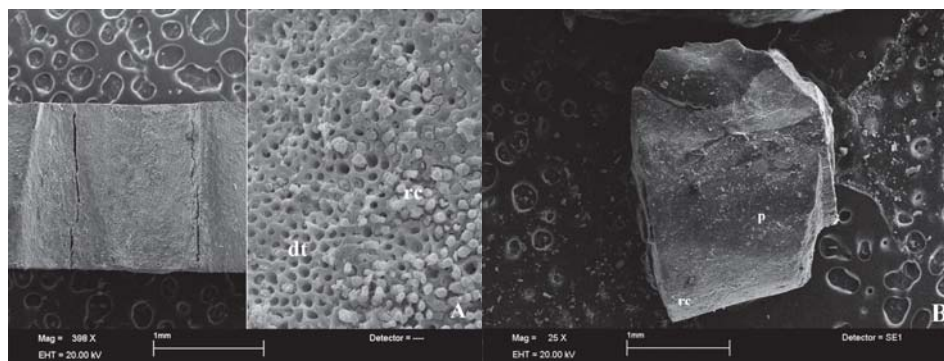


Figure 4. (A) Micrograph of a mixed failure in the RX/LI group showing part of dentin with exposure of dentinal tubules (dt) and the dentin partly filled by resinous cement (rc) (right). (B) Adhesive failure between dentin/cement showing part of an intra-radicular post (p) of the CP/LI group partially enveloped by resinous cement (rc).